

Methodology, advantages and limitations of in-situ XRF measurements (including overview of applications)

Tuesday, 27 October 2009 09:00 (1:30)

Content

Summary

Primary author(s) : R. PADILLA-ALVAREZ (Agency's Seibersdorf Laboratory, IAEA, Austria)

Presenter(s) : R. PADILLA-ALVAREZ (Agency's Seibersdorf Laboratory, IAEA, Austria)

Session Classification : Methodology, advantages and limitations of in-situ XRF measurements (including overview of applications)